

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)ATTY DOCKET NO.  
**862.2480**APPLICATION NO.  
**09/161,405**APPLICANT  
**HIRAKU KOZUKA****RECEIVED**FILING DATE  
**September 28, 1998**GROUP  
**2812 JUN 02 1999**

## U.S. PATENT DOCUMENTS

PATENT & TRADEMARK OFFICE  
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*EXAMINER INITIAL	DOCUMENT NUMBER	NAME	CLASS	Subclass	Group 2790 FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLATION YES/NO/ OR ABSTRACT

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

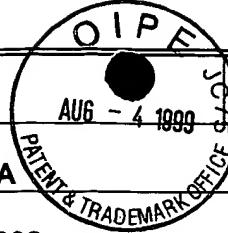
JW	Shin Kikuchi et al. "High Speed, High Gradation Contact Type Linear Sensor BASIS Multi-Chip Contact Sensor", Journal of Television Society, Vol. 47, No. 9, (1993), pp. 1177-1182, in Japanese with English Abstract.

EXAMINER

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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JTW		4,584,607	4/22/86	Miyazawa	358	209	AUG - 9 1999
						2700 MAIL ROOM	RECEIVED

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JTW		3-280663	12/11/91	Japan	—	—	Abstract
JTW		62-115865	5/27/87	Japan	—	—	Abstract
JTW		61-214657	9/24/86	Japan	—	—	Abstract
JTW		0741493	11/6/96	Europe	—	—	
JTW		0488674	6/3/92	Europe	—	—	

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

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